

# IGBT<sup>3</sup> Chip

### FEATURES:

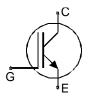
- 600V Trench & Field Stop technology
- low V<sub>CE(sat)</sub>
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

### This chip is used for:

- power module
- discrete components

### Applications:

- drives
- white goods
- resonant applications



| Chip Type  | V <sub>CE</sub> | I <sub>Cn</sub> | Die Size                    | Package      | Ordering Code         |
|------------|-----------------|-----------------|-----------------------------|--------------|-----------------------|
| SIGC06T60G | 600V            | 10A             | 2.44 x 2.42 mm <sup>2</sup> | sawn on foil | Q67050-<br>A4344-A101 |

## **MECHANICAL PARAMETER:**

| Raster size                     | 2.44 x 2.42  |                 |  |  |
|---------------------------------|--|-----------------|--|--|
| Emitter pad size                | 1.558 x 1.577  | mm <sup>2</sup> |  |  |
| Gate pad size                   | 0.361 x 0.513  |                 |  |  |
| Area total / active             | 5.9 / 3.6  |                 |  |  |
| Thickness                       | 70   | μm              |  |  |
| Wafer size                      | 150  | mm              |  |  |
| Flat position                   | 0  | deg             |  |  |
| Max. possible chips per wafer   | 2485 pcs   |                 |  |  |
| Passivation frontside           | Photoimide   |                 |  |  |
| Emitter metallization           | 3200 nm AlSiCu   |                 |  |  |
| Collector metallization         | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding                         |                 |  |  |
| Die bond                        | electrically conductive glue or solder   |                 |  |  |
| Wire bond                       | AI, <500µm   |                 |  |  |
| Reject ink dot size             | Ø 0.65mm ; max 1.2mm   |                 |  |  |
| Recommended storage environment | store in original container, in dry nitrogen,<br>< 6 month at an ambient temperature of 23°C |                 |  |  |



#### **MAXIMUM RATINGS:**

| Parameter   | Symbol             | Value    | Unit |      |  |
|---|--------------------|----------|------|------|--|
| Collector-emitter voltage, $T_j$ = 25 °C              | V <sub>CE</sub>    | 600      | V    |      |  |
| DC collector current, limited by $T_{j\text{max}}$    | I <sub>C</sub>     | 1)       | А    |      |  |
| Pulsed collector current, $t_p$ limited by $T_{jmax}$ | I <sub>cpuls</sub> | 30       | А    |      |  |
| Gate emitter voltage                                  | V <sub>GE</sub>    | ±20      | V    |      |  |
| Operating junction and storage temperatur             | $T_{j}, T_{stg}$   | -40 +175 | °C   |      |  |
| SC data, $V_{GE} = 15V$ , $V_{CC} = 360V$             | Tvj = 150°C        | to       | 6    | - µs |  |
| Se data, $v_{GE} = 15v$ , $v_{CC} = 300v$             | Tvj = 25°C         | - tp     | 8    |      |  |

<sup>1)</sup> depending on thermal properties of assembly

## STATIC CHARACTERISTICS (tested on chip), $T_j$ =25 °C, unless otherwise specified

| Parameter                            | Symbol               | Conditions                                 | Value |      |      | Unit |
|--------------------------------------|----------------------|--|-------|------|------|------|
| Tarameter                            |                      |  | min.  | typ. | max. |      |
| Collector-emitter breakdown voltage  | V <sub>(BR)CES</sub> | $V_{GE}$ =0V , I <sub>C</sub> = 2mA        | 600   |      |      |      |
| Collector-emitter saturation voltage | V <sub>CE(sat)</sub> | V <sub>GE</sub> =15V, I <sub>C</sub> =10A  | 1.1   | 1.5  | 1.9  | V    |
| Gate-emitter threshold voltage       | V <sub>GE(th)</sub>  | $I_C$ =150 $\mu$ A , $V_{GE}$ = $V_{CE}$   | 5.0   | 5.8  | 6.5  |      |
| Zero gate voltage collector current  | I <sub>CES</sub>     | $V_{CE}$ =600V , $V_{GE}$ =0V              |       |      | 0.6  | μA   |
| Gate-emitter leakage current         | I <sub>GES</sub>     | V <sub>CE</sub> =0V , V <sub>GE</sub> =20V |       |      | 300  | nA   |
| Integrated gate resistor             | R <sub>Gint</sub>    |  |       | none |      | Ω    |

### **ELECTRICAL CHARACTERISTICS** (verified by design/characterization):

| Parameter                    | Symbol | Conditions            | Value |      |      | Unit |
|------------------------------|--------|-----------------------|-------|------|------|------|
| raiameter                    |        |                       | min.  | typ. | max. | Unit |
| Input capacitance            | Ciss   | V <sub>CE</sub> =25V, |       | 551  |      | pF   |
| Output capacitance           | Coss   | $V_{\rm GE}=0V$ ,     |       | 40   |      |      |
| Reverse transfer capacitance | Crss   | <i>f</i> =1MHz        |       | 17   |      | 1    |

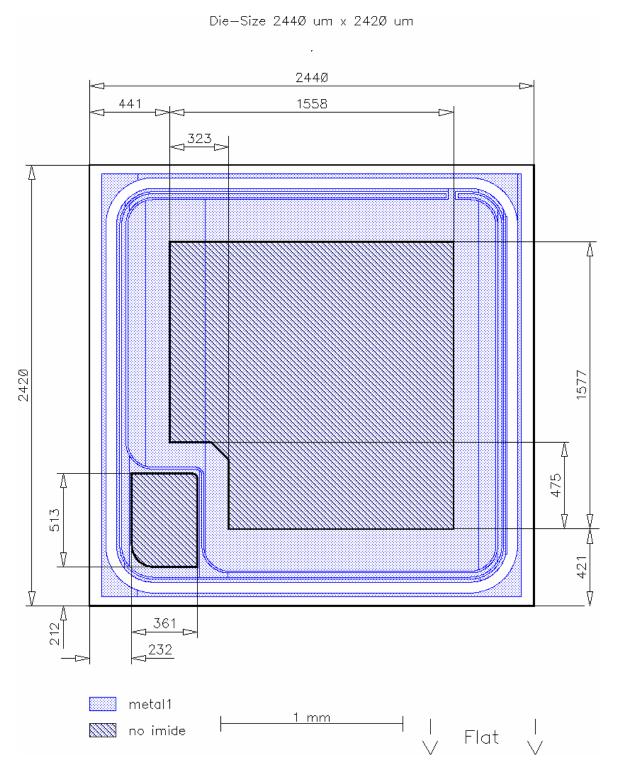
### SWITCHING CHARACTERISTICS (verified by design/characterization), inductive load

| Parameter           | Symbol              | Conditions  | Value <sup>2)</sup> |      |      | Unit |
|---------------------|---------------------|---|---------------------|------|------|------|
| ralameter           |                     |   | min.                | typ. | max. |      |
| Turn-on delay time  | t <sub>d(on)</sub>  | $T_j = 125 \circ C$   |                     | 12   |      | ns   |
| Rise time           | tr                  | V <sub>cc</sub> =300V,<br>I <sub>c</sub> =10A,<br>V <sub>GE</sub> =-15/15V, |                     | 13   |      |      |
| Turn-off delay time | t <sub>d(off)</sub> | $V_{GF} = -15/15V$ ,  |                     | 120  |      |      |
| Fall time           | t <sub>f</sub>      | $R_{\rm G}$ = 27 $\Omega$   |                     | 130  |      |      |

 $^{\mbox{\tiny 2)}}$  values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





#### FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the |  |
|------------------------------------|--|
| device data sheet                  |  |

#### **DESCRIPTION:**

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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